

# Characterization of anisotropic short-range order in amorphous $\text{SmFe}_2$ films with various magnetic anisotropy

東工大工学院<sup>1</sup> ○高村 陽太<sup>1</sup>, (M2)小野澤 隼<sup>1</sup>, (M1)浦下 宗輝<sup>1</sup>, 中川 茂樹<sup>1</sup>

Tokyo Tech<sup>1</sup>, °Yota Takamura<sup>1</sup>, Hayato Onozawa<sup>1</sup>, Soki Urashita<sup>1</sup>, Shigeki Nakagawa<sup>1</sup>

E-mail: takamura@ee.e.titech.ac.jp

Perpendicular magnetic tunnel junctions with a giant negative magnetostrictive free layer with the sidewall of piezoelectric materials, piezoelectronic tunnel junctions (PE-MTJ) [1], is attractive MTJ since it can overcome the intrinsic problem of keeping high thermal stability and reducing critical current density for magnetization switching. We have been studied  $\text{SmFe}_2$  thin films as a promising material for the free layer of PE-MTJ, and obtained  $\text{SmFe}_2$  thin films with perpendicular magnetic anisotropy (PMA) and giant negative magnetostriction simultaneously. However, the origin of the anisotropy is not understood, since the  $\text{SmFe}_2$  thin films have amorphous structure according to X-ray diffraction and transmission electron microscopy analysis. In this study, we analyzed short-range order in the  $\text{SmFe}_2$  thin films with various magnetic anisotropy using polarized extended X-ray absorption fine structure (EXAFS) measurements.

The stack structure of the samples is Quartz-sub./W/ $\text{SmFe}_2$ /W. The substrate temperature  $T_s$  during sputtering was varied from 200 to 400°C so that easy axis of magnetic anisotropy changed from out-of-plane to in-plane directions. The post annealing temperature was fixed at 500°C. EXAFS measurements for the Sm-L3 edge were done at a beamline BL-9C in High Energy Accretor Research Organization (KEK).

The EXAFS signals were well fitted with a single Sm-Fe path using QFC model. Figure 1 shows the distance  $R$  between Sm and Fe atoms and the coordination number  $N$  of Sm as function of  $T_s$ . For the sample formed  $T_s = 200$  and 300°C with PMA,  $R$  for out-of-plane and in-plane are different. On the other, the sample formed at 400°C with in-plane magnetic anisotropy,  $R$  was identical. The  $N$  of all the sample for both directions were identical which seems not to contributed to the magnetic anisotropy in this case.

The analysis implies that the  $\text{SmFe}_2$  films with PMA have tensile stress, which strengthens magnetic anisotropy in the out-of-plane direction via the negative magnetostrictive effect, resulting in PMA.

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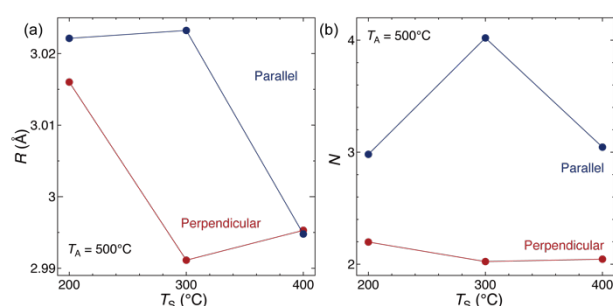


Fig. 1 EXAFS analysis. (a) the distance  $R$  between Sm and Fe atoms (b) the coordination number  $N$  around Sm atoms as a function of substrate temperature  $T_s$ .

## References

- [1] Y. Takamura, et al., Solid State Electron., **128**, 194 (2017).
- [2] Y. Takamura, et al., "Perpendicular magnetic anisotropy of giant negative magnetostrictive  $\text{SmFe}_2$  amorphous thin films," to be submitted in 2020.